

**FUJITSU
MICROELECTRONICS**
2SC2427

3749762 FUJITSU MICROELECTRONICS

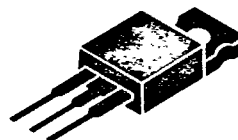
37C 01753

**SILICON HIGH SPEED TRIPLE DIFFUSED
NPN POWER TRANSISTORS 7 AMP, 400 VOLT**

T-33-11

ABSOLUTE MAXIMUM RATINGS

Ratings	Symbol	Condition	Value	Unit
			2SC2427	
Collector-Base Voltage	V_{CBO}		500	V
Emitter-Base Voltage	V_{EBO}		7	V
Collector-Emitter Voltage	V_{CEO}		400	V
Collector Current-Continuous	I_C		7	A
Collector Current-Peak	I_{CM}	Pulsed	15	A
Base Current	I_B		3	A
Collector Power Dissipation	P_C	$T_C=25^\circ\text{C}$	40	W
Junction Temperature	T_j		150	$^\circ\text{C}$
Storage Temperature Range	T_{stg}		-55~+150	$^\circ\text{C}$


ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$)

Characteristics	Symbol	Test Conditions	LIMITS			Unit
			2SC2427			
			MIN	TYP	MAX	
Collector Cutoff Current	I_{CBO}	$V_{CB}=450V, I_E=0$	—	—	10	μA
Emitter Cutoff Current	I_{EBO}	$V_{EB}=5V, I_C=0$	—	—	10	μA
Collector Cutoff Current	I_{CEO}	$V_{CE}=320V, I_B=0$	—	—	500	μA
Collector-Base Breakdown Voltage	V_{CBO}	$I_C=100\mu A, I_E=0$	500	—	—	V
Emitter-Base Breakdown Voltage	V_{EBO}	$I_E=100\mu A, I_C=0$	7	—	—	V
Collector-Emitter Breakdown Voltage	V_{CEO}	$I_C=10mA, R_{BE}=\infty$	400	—	—	V
Collector-Emitter Breakdown Voltage	$V_{CEO(SUS)}$	$I_C=100mA, R_{BE}=\infty$	400	—	—	V
DC Current Gain	h_{FE}	$V_{CE}=5V, I_C=2A$ *	10	20	40	—
Output Capacitance	C_{ob}	$V_{CB}=20V, I_E=0, f=1MHz$	—	90	—	PF
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C=2A, I_B=0.4$ *	—	0.2	0.7	V
Base-Emitter Saturation Voltage	$V_{BE(sat)}$		—	0.9	1.2	V
Gain-Bandwidth Product	f_T	$V_{CE}=10V, I_E=0.5A$	—	20	—	MHz
Rise Time	t_r	$I_C=2A, V_{CC}=150V$ $I_{B1}=-I_{B2}=0.4A$	—	0.3	1.0	μS
Storage Time	t_{stg}		—	2.2	3.0	μS
Fall Time	t_f		—	0.4	1.0	μS

* pulsed: pulse width $\leq 300\mu\text{S}$, Duty cycle $\leq 2\%$

PACKAGE TYPE: TO-220. See page 5-23 for dimensions.

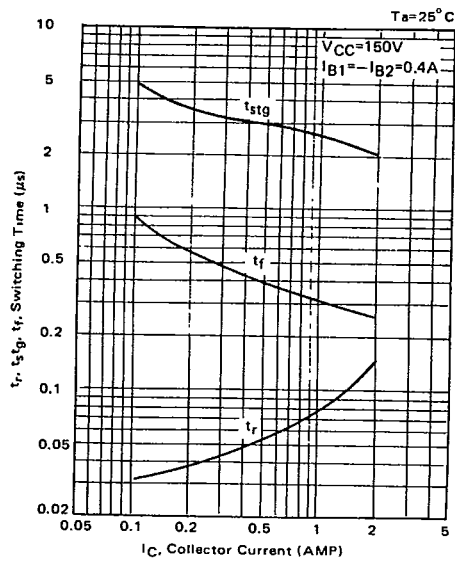
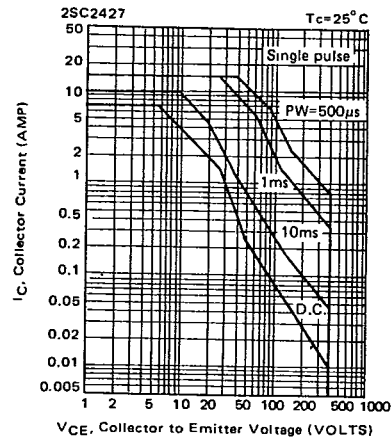
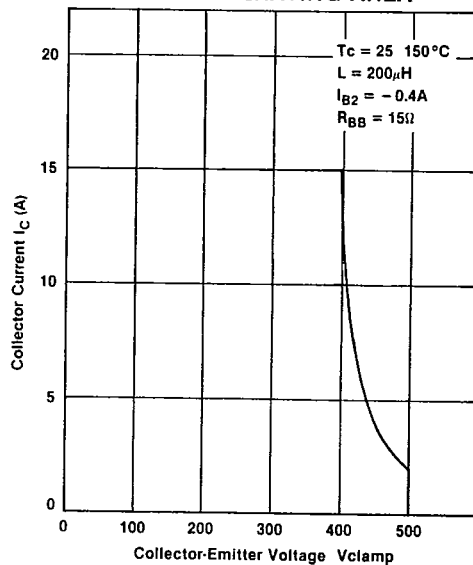
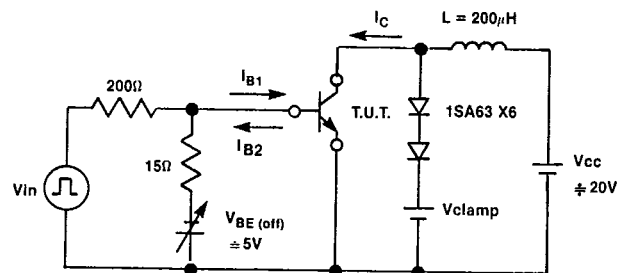
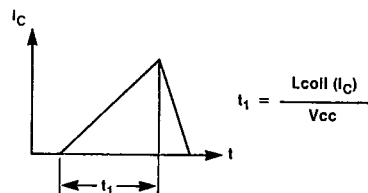
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T-33-11^D

SWITCHING TIME (with constant base drive)

2SC2427
SAFE OPERATING AREAS2SC2427 REVERSE BIAS
SAFE OPERATING AREATEST CIRCUIT FOR MEASUREMENT OF
REVERSE BIAS SAFE OPERATING AREA t_1 ADJUSTED TO OBTAIN I_C 

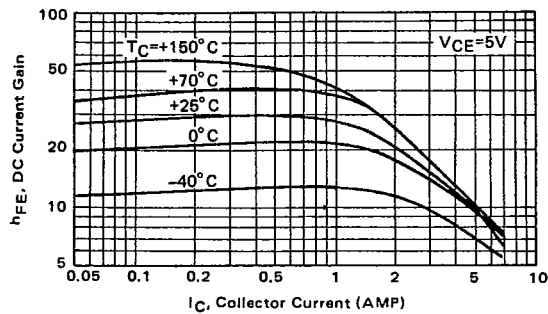
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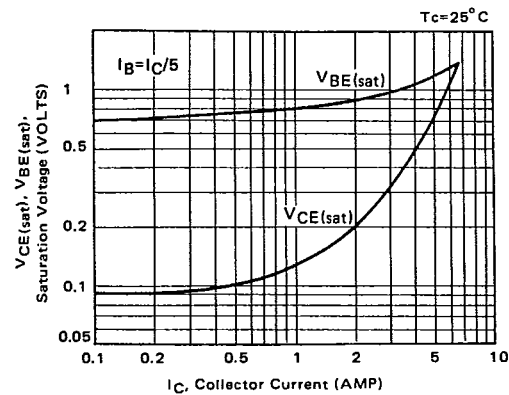
2SC2427

T-33-11^D

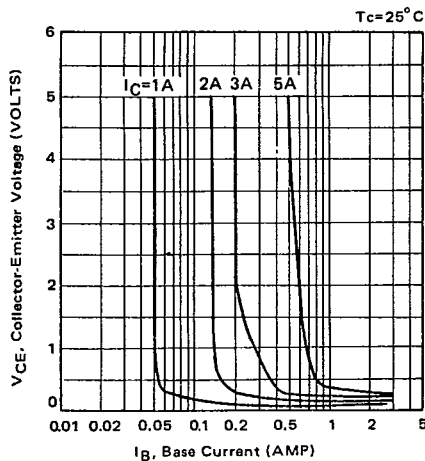
DC CURRENT GAIN



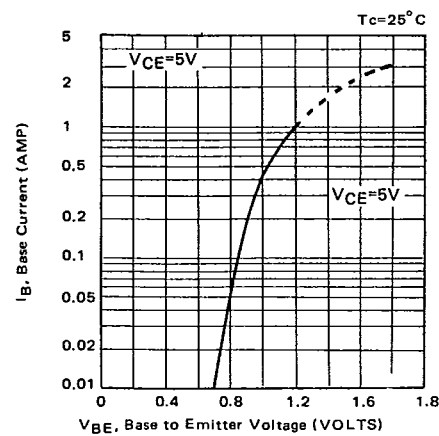
SATURATION VOLTAGE



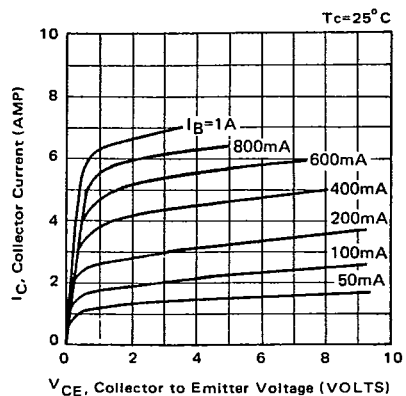
COLLECTOR TO EMITTER SATURATION VOLTAGE



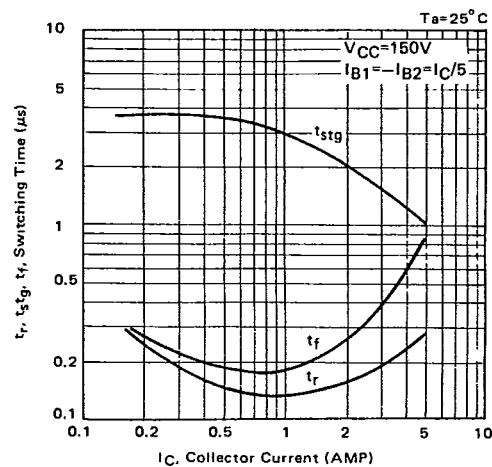
INPUT CHARACTERISTICS



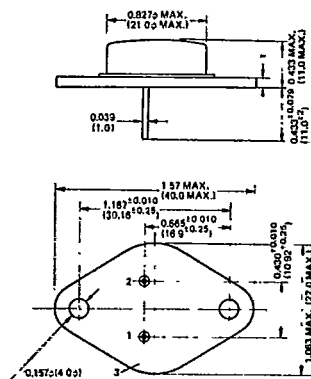
OUTPUT CHARACTERISTICS



SWITCHING TIME

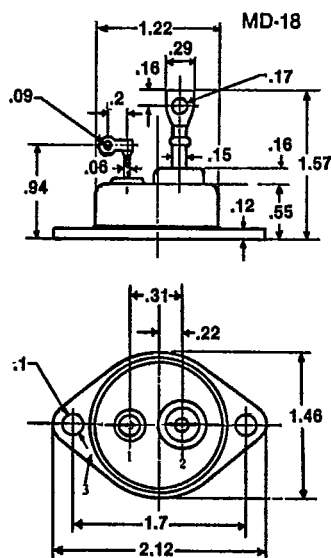


JEDEC TO-3

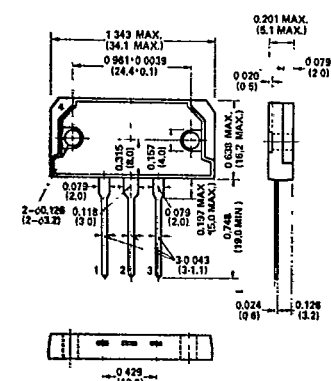


1: Base 2: Emitter 3: Collector (Case)
Dimension in inches and (millimeters)

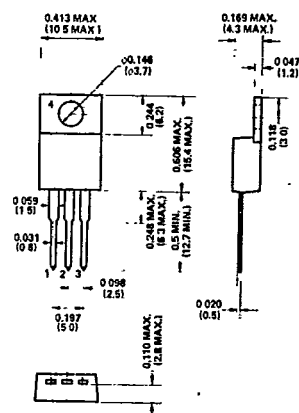
MD-18



1: Base 2: Emitter 3: Collector

RM-60

1: Base 2: Collector 3: Emitter 4: Fin (Collector)
Dimension in inches and (millimeters)

JEDEC TO-220

1: Base 2: Collector 3: Emitter 4: Fin (Collector)
Dimension in inches and (millimeters)